



Integrated Device Technology, Inc.

3.3V CMOS 20-BIT BUFFERS

IDT74FCT163827A/B/C

FEATURES:

- 0.5 MICRON CMOS Technology
- **Typical tsk(o) (Output Skew) < 250ps**
- ESD > 2000V per MIL-STD-883, Method 3015;
> 200V using machine model (C = 200pF, R = 0)
- Packages include 25 mil pitch SSOP, 19.6 mil pitch TSSOP and 15.7 mil pitch TVSOP
- Extended commercial range of -40°C to +85°C
- Vcc = 3.3V ±0.3V, Normal Range or
Vcc = 2.7 to 3.6V, Extended Range
- CMOS power levels (0.4µW typ. static)
- Rail-to-Rail output swing for increased noise margin
- Low Ground Bounce (0.3V typ.)
- Inputs (except I/O) can be driven by 3.3V or 5V
components

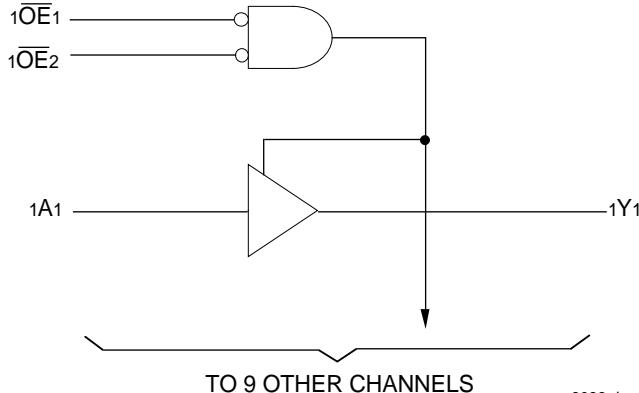
DESCRIPTION:

The FCT163827A/B/C 20-bit buffers are built using advanced dual metal CMOS technology. These 20-bit bus drivers provide high-performance bus interface buffering for wide data/address paths or busses carrying parity. Two pairs of NAND-ed output enable controls offer maximum control flexibility and are organized to operate the device as two 10-bit buffers or one 20-bit buffer. Flow-through organization of signal pins simplifies layout. All inputs are designed with hysteresis for improved noise margin.

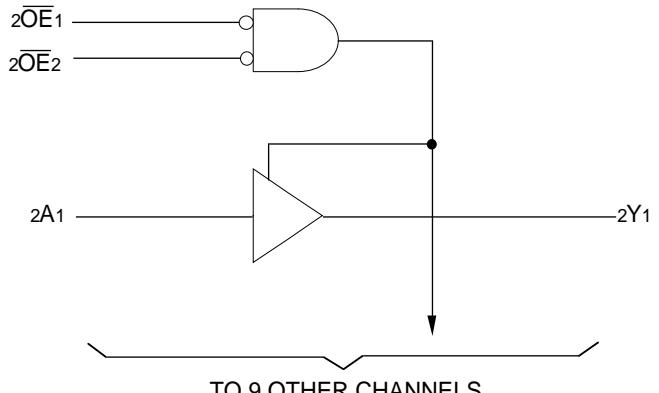
The FCT163827A/B/C have series current limiting resistors. This offers low ground bounce, minimal undershoot, and controlled output fall times—reducing the need for external series terminating resistors.

The inputs of the FCT163827A/B/C can be driven from either 3.3V or 5V devices. This feature allows the use of these devices as translators in a mixed 3.3V/5V supply system.

FUNCTIONAL BLOCK DIAGRAM



3083 drw 01



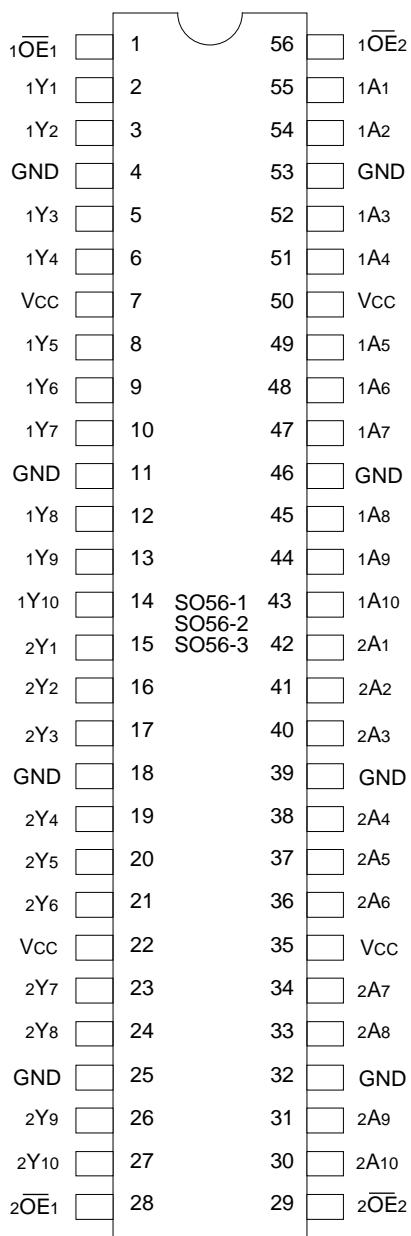
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COMMERCIAL TEMPERATURE RANGE

AUGUST 1996

PIN CONFIGURATIONS



SSOP/
TSSOP/TVSOP
TOP VIEW

3083 drw 03

CAPACITANCE ($T_A = +25^\circ C$, $f = 1.0\text{MHz}$)

Symbol	Parameter ⁽¹⁾	Conditions	Typ.	Max.	Unit
C _{IN}	Input Capacitance	$V_{IN} = 0V$	3.5	6.0	pF
C _{OUT}	Output Capacitance	$V_{OUT} = 0V$	3.5	8.0	pF

NOTE:

1. This parameter is measured at characterization but not tested.

PIN DESCRIPTION

Pin Names	Description
x $\overline{OE}x$	Output Enable Inputs (Active LOW)
xAx	Data Inputs
xYx	3-State Outputs

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ABSOLUTE MAXIMUM RATINGS⁽¹⁾

Symbol	Description	Max.	Unit
VTERM ⁽²⁾	Terminal Voltage with Respect to GND	-0.5 to +4.6	V
VTERM ⁽³⁾	Terminal Voltage with Respect to GND	-0.5 to +7.0	V
VTERM ⁽⁴⁾	Terminal Voltage with Respect to GND	-0.5 to Vcc + 0.5	V
TSTG	Storage Temperature	-65 to +150	°C
I _{OUT}	DC Output Current	-60 to +60	mA

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- NOTES:
1. Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.
 2. Vcc terminals.
 3. Input terminals.
 4. Output and I/O terminals.

FUNCTION TABLE⁽¹⁾

Inputs			Outputs	
$x\overline{OE}1$	$x\overline{OE}2$	xAx	xYx	
L	L	L	L	
L	L	H	H	
H	X	X	Z	
X	H	X	Z	

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- NOTE:
1. H = HIGH Voltage Level
L = LOW Voltage Level
X = Don't Care
Z = High Impedance

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DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:
Commercial: TA = -40°C to $+85^{\circ}\text{C}$, V_{CC} = 2.7V to 3.6V

Symbol	Parameter	Test Conditions ⁽¹⁾		Min.	Typ. ⁽²⁾	Max.	Unit
V _{IH}	Input HIGH Level (Input pins)	Guaranteed Logic HIGH Level	2.0	—	5.5	V	
	Input HIGH Level (I/O pins)		2.0	—	V _{CC} +0.5		
V _{IL}	Input LOW Level (Input and I/O pins)	Guaranteed Logic LOW Level		-0.5	—	0.8	V
I _{IH}	Input HIGH Current (Input pins)	V _{CC} = Max.	V _I = 5.5V	—	—	± 1	μA
	Input HIGH Current (I/O pins)		V _I = V _{CC}	—	—	± 1	
I _{IL}	Input LOW Current (Input pins)	V _I = GND	V _I = GND	—	—	± 1	
	Input LOW Current (I/O pins)		V _I = GND	—	—	± 1	
I _{OZH}	High Impedance Output Current (3-State Output pins)	V _{CC} = Max.	V _O = V _{CC}	—	—	± 1	μA
I _{OZL}			V _O = GND	—	—	± 1	
V _{IK}	Clamp Diode Voltage	V _{CC} = Min., I _{IN} = -18mA		—	-0.7	-1.2	V
I _{ODH}	Output HIGH Current	V _{CC} = 3.3V, V _{IN} = V _{IH} or V _{IL} , V _O = 1.5V ⁽³⁾		-36	-60	-110	mA
I _{OL}	Output LOW Current	V _{CC} = 3.3V, V _{IN} = V _{IH} or V _{IL} , V _O = 1.5V ⁽³⁾		50	90	200	mA
V _{OH}	Output HIGH Voltage	V _{CC} = Min.	I _{OH} = -0.1mA	V _{CC} -0.2	—	—	V
		V _{IN} = V _{IH} or V _{IL}	I _{OH} = -3mA	2.4	3.0	—	
		V _{CC} = 3.0V	I _{OH} = -8mA	2.4 ⁽⁵⁾	3.0	—	
V _{OL}	Output LOW Voltage	V _{CC} = Min.	I _{OL} = 0.1mA	—	—	0.2	V
		V _{IN} = V _{IH} or V _{IL}	I _{OL} = 16mA	—	0.2	0.4	
			I _{OL} = 24mA	—	0.3	0.55	
		V _{CC} = 3.0V	I _{OL} = 24mA	—	0.3	0.50	
I _{OS}	Short Circuit Current ⁽⁴⁾	V _{CC} = Max., V _O = GND ⁽³⁾		-60	-135	-240	mA
V _H	Input Hysteresis	—		—	150	—	mV
I _{ICCL} I _{ICCH} I _{ICCZ}	Quiescent Power Supply Current	V _{CC} = Max., V _{IN} = GND or V _{CC}		—	0.1	10	μA

NOTES:

- For conditions shown as Max. or Min., use appropriate value specified under Electrical Characteristics for the applicable device type.
- Typical values are at V_{CC} = 3.3V, +25°C ambient.
- Not more than one output should be tested at one time. Duration of the test should not exceed one second.
- This parameter is guaranteed but not tested.
- V_{OH} = V_{CC} - 0.6V at rated current.

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POWER SUPPLY CHARACTERISTICS

Symbol	Parameter	Test Conditions ⁽¹⁾		Min.	Typ. ⁽²⁾	Max.	Unit
ΔI_{CC}	Quiescent Power Supply Current TTL Inputs HIGH	Vcc = Max.	VIN = Vcc - 0.6V ⁽³⁾	—	2.0	30	μA
I _{CCD}	Dynamic Power Supply Current ⁽⁴⁾	Vcc = Max. Outputs Open $xO\bar{E}1 = x\bar{O}E2 = GND$ One Input Toggling 50% Duty Cycle	VIN = VCC VIN = GND	—	50	75	$\mu A / MHz$
I _C	Total Power Supply Current ⁽⁶⁾	Vcc = Max. Outputs Open $f_i = 10MHz$ 50% Duty Cycle $xO\bar{E}1 = x\bar{O}E2 = GND$ One Bit Toggling	VIN = VCC VIN = GND	—	0.5	0.7	mA
		VIN = VCC - 0.6V VIN = GND	—	0.5	0.8		
		Vcc = Max. Outputs Open $f_i = 2.5MHz$ 50% Duty Cycle $xO\bar{E}1 = x\bar{O}E2 = GND$ Twenty Bits Toggling	VIN = VCC VIN = GND	—	2.5	3.7 ⁽⁵⁾	
		VIN = VCC - 0.6V VIN = GND	—	2.5	4.1 ⁽⁵⁾		

NOTES:

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1. For conditions shown as max. or min., use appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical values are at Vcc = 3.3V, +25°C ambient.

3. Per TTL driven input; all other inputs at Vcc or GND.

4. This parameter is not directly testable, but is derived for use in Total Power Supply Calculations.

5. Values for these conditions are examples of the I_{CC} formula. These limits are guaranteed but not tested.

6. $I_C = I_{QUIESCENT} + I_{INPUTS} + I_{DYNAMIC}$

$$I_C = I_{CC} + \Delta I_{CC} D_{HNT} + I_{CCD} (f_{CP} N_{CP}/2 + f_i N_i)$$

I_{CC} = Quiescent Current (I_{CCL} , I_{CCH} and I_{CCZ})

ΔI_{CC} = Power Supply Current for a TTL High Input

D_H = Duty Cycle for TTL Inputs High

N_T = Number of TTL Inputs at D_H

I_{CCD} = Dynamic Current Caused by an Input Transition Pair (HLH or LHL)

f_{CP} = Clock Frequency for Register Devices (Zero for Non-Register Devices)

N_{CP} = Number of Clock Inputs at f_{CP}

f_i = Input Frequency

N_i = Number of Inputs at f_i

SWITCHING CHARACTERISTICS OVER OPERATING RANGE⁽⁴⁾

Symbol	Parameter	Conditions ⁽¹⁾	FCT163827A		FCT163827B		FCT163827C		Unit
			Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.	
tPLH tPHL	Propagation Delay xAx to xYx	CL = 50pF RL = 500Ω	1.5	8.0	1.5	5.0	1.5	4.4	ns
		CL = 300pF ⁽⁴⁾ RL = 500Ω	1.5	15.0	1.5	13.0	1.5	10.0	
tPZH tPZL	Output Enable Time xOĒx to xYx	CL = 50pF RL = 500Ω	1.5	12.0	1.5	8.0	1.5	7.0	ns
		CL = 300pF ⁽⁴⁾ RL = 500Ω	1.5	23.0	1.5	15.0	1.5	14.0	
tPHZ tPLZ	Output Disable Time xOĒx to xYx	CL = 5pF ⁽⁴⁾ RL = 500Ω	1.5	9.0	1.5	6.0	1.5	5.7	ns
		CL = 50pF RL = 500Ω	1.5	10.0	1.5	7.0	1.5	6.0	
tsk(o)	Output Skew ⁽³⁾		—	0.5	—	0.5	—	0.5	ns

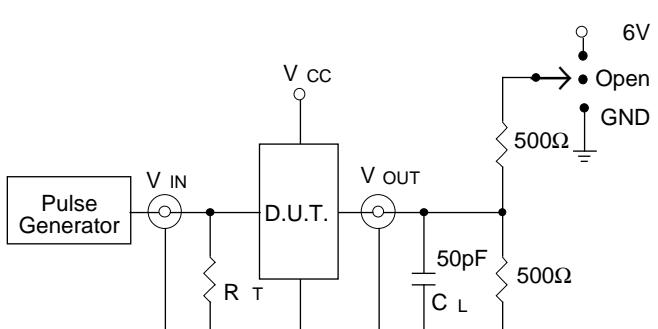
NOTES:

1. See test circuit and waveforms.
2. Minimum limits are guaranteed but not tested on Propagation Delays.
3. Skew between any two outputs, of the same package, switching in the same direction. This parameter is guaranteed by design.
4. Propagation Delays and Enable/Disable times are with $V_{CC} = 3.3V \pm 0.3V$, Normal Range. For $V_{CC} = 2.7V$ to $3.6V$, Extended Range, all Propagation Delays and Enable/Disable times should be degraded by 20%.

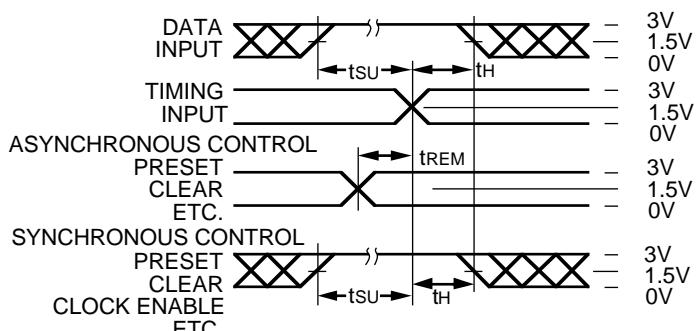
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TEST CIRCUITS AND WAVEFORMS

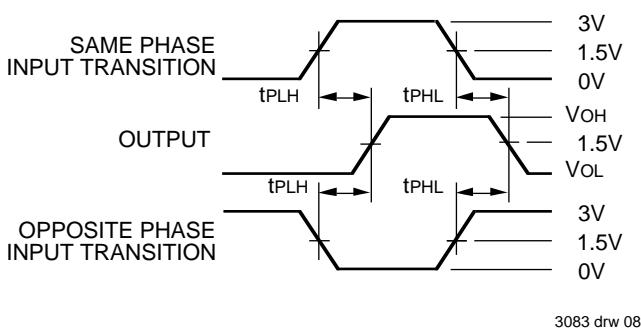
TEST CIRCUITS FOR ALL OUTPUTS



SET-UP, HOLD AND RELEASE TIMES



PROPAGATION DELAY



SWITCH POSITION

Test	Switch
Open Drain	Open
Disable Low	6V
Enable Low	GND
Disable High	GND
Enable High	Open
All Other tests	Open

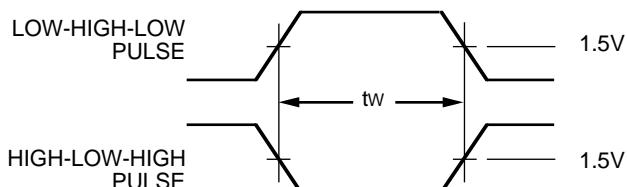
DEFINITIONS:

CL = Load capacitance: includes jig and probe capacitance.

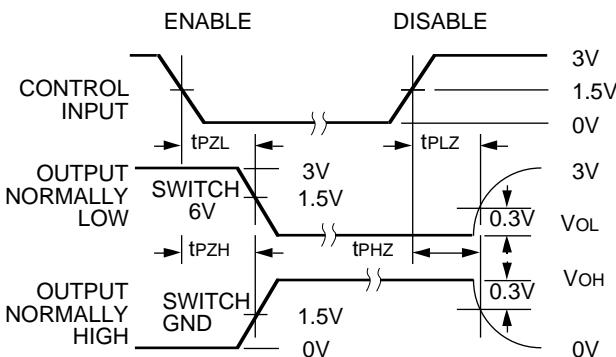
RT = Termination resistance: should be equal to ZOUT of the Pulse Generator.

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PULSE WIDTH



ENABLE AND DISABLE TIMES



NOTES:

1. Diagram shown for input Control Enable-LOW and input Control Disable-HIGH.
2. Pulse Generator for All Pulses: Rate $\leq 1.0\text{MHz}$; $t_f \leq 2.5\text{ns}$; $t_r \leq 2.5\text{ns}$.
3. If V_{cc} is below 3V, input voltage swings should be adjusted not to exceed V_{cc} .

ORDERING INFORMATION

IDT	XX	FCT	XXXX	X	
Temp. Range		Device Type		Package	
				PV	Shrink Small Outline Package (SO56-1)
				PA	Thin Shrink Small Outline Package (SO56-2)
				PF	Thin Very Small Outline Package (SO56-3)
			163827A 163827B 163827C		Non-Inverting 20-Bit Buffers
		74			-40°C to +85°C

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